

# Residual conductance of correlated one-dimensional nanosystems

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# Low-dimensional mesoscopic systems



- electronic transport is coherent
- electronic correlations may become important

# Transport through interacting region



difficulties:

- excitations in the interacting region possible not for zero-bias conductance at T = 0
- coupling to leads → open system embedding method [Favand, Mila 1998]



# Overview

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- 2 Embedding method
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- 3 Some basic aspects of transport through a correlated region
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# Conductance of a coherent channel Conductance per open channel: Coherent transport Persistent current $\frac{e^2}{h}$ Test of the method Even-odd effects $V_1 \circ - \circ V_2$ two-terminal conductance four-terminal conductance $G = \frac{I}{V_a - V_b} = \frac{e^2}{h} \frac{T}{1 - T}$ $G = \frac{I}{V_1 - V_2} = \frac{e^2}{h}T$ $G = \frac{I}{V_1 - V_2} = \frac{e^2}{h}T$ accounts for contact resistance Flux-threaded ring $E(\phi)$ Persistent current $\Phi = \frac{\phi}{\phi_0}, \quad \phi_0 = \frac{h}{e}$ Even-odd effects $J = -\frac{\partial E}{\partial \phi}$ $\phi_0/2$ $-\phi_0/2$ persistent current: ψ $c = -\frac{\partial^2 E}{\partial \phi^2}$ curvature: charge stiffness: $D = (-1)^N \frac{L}{2} (E(0) - E(\pi))$

## Kohn conductivity



time-dependent flux:

$$\phi \sim \frac{E \mathrm{e}^{\mathrm{i}\omega t}}{\mathrm{i}\omega}$$



→ current response:  $J = \sigma E e^{i\omega t}$ 

with  $\lim_{\omega \to 0} \omega \sigma''(\omega) \sim -\frac{\partial^2 E}{\partial \phi^2}$  Drude weight

- curvature is a measure of the number of extended states
- paramagnetic or diamagnetic response possible







Some basic concepts Coherent transpor Persistent current

Embedding method Transmission

Test of the method

Outside half filling Even-odd effects Contacts Disorder & interaction

Atomic chains

Conclusions

### How and why does the embedding method work?



interacting part, length  $L_{\rm S}$ 

Transmission Test of the method

Outside half filling

persistent current takes into account

- number of extended states
- contacts between interacting region and lead

embedding setup = tool to determine transmission

- no decoherence in the lead
- no Luttinger correlations in the noninteracting part

# Persistent current and transmission

point scatterer with transmission *t* in a noninteracting ring [Gogolin, Prokof'ev 1994]

$$J(\Phi, N \text{ odd}) = -\frac{ev_{\text{F}}}{\pi L} \frac{\operatorname{Arccos}(|t(E_{\text{F}})|\cos(\Phi))}{\sqrt{1 - |t(E_{\text{F}})|^2\cos^2(\Phi)}} |t(E_{\text{F}})|\sin(\Phi)|$$

 $J(\Phi, N \text{ even}) = J(\Phi - \pi; N \text{ odd})$ 

conductance:

$$g = \lim_{L_{\rm L}\to\infty} \left(\frac{J(\pi/2)}{J^0(\pi/2)}\right)^2$$

 $(J^0:$  persistent current of clean ring)

requires complex DMRG algorithm

Charge stiffness and transmission

relation to transmission:

$$D = \frac{\hbar v_{\rm F}}{2} \left[ \frac{\pi}{2} - \operatorname{Arccos}(|t(E_F)|) \right]$$

conductance:

$$g = \lim_{L_{\rm L}\to\infty} \sin^2\left(\frac{\pi}{2}\frac{D}{D^0}\right)$$

real DMRG algorithm sufficient







Some basic concepts

Persistent current

Embedding method

**Transmission** Test of the method

Basic aspects Outside half filling Even-odd effects Contacts Disorder & interaction

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# A few references on the embedding method

- J. Favand, F. Mila, Eur. Phys. J. B 2, 293 (1998)
- O. P. Sushkov, Phys. Rev. B 64, 155319 (2001)
- R. A. Molina et al., Phys. Rev. B 67, 235306 (2003)
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Transmission Test of the method

Outside half filling

# Spinless fermions



$$H = -t \sum_{i=1}^{L} \left( c_i^{\dagger} c_{i-1}^{\dagger} + c_{i-1}^{\dagger} c_i \right) + \sum_{i=2}^{L_{\rm S}} U(n_i - V_+) (n_{i-1} - V_+)$$

boundary condition:  $c_0 = e^{i\Phi} c_L$ 

v = 1/2 $V_+ = 1/2$  (particle-hole symmetry) $v \neq 1/2$  $V_+$  must be determined by iteration

# Scaling to infinite ring length (I)

half filling (v = 1/2),  $L_S = 6$ 



Scaling to infinite ring length (II)

linear scaling for charge stiffness





Persistent current

Test of the method

Even-odd effects

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→ interacting region can be described by an effective point scatterer with transmission *t* 



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# Some basic aspects of transport through a correlated region

# Outside half filling



- signature of Mott transition
- suppression of the conductance is most effective at half filling



# Influence of contacts



 $\rightarrow$  smoothing of the contacts increases the conductance



Persistent current

Transmission

Test of the method

Even-odd effects Contacts

# Disorder and interaction



## $\rightarrow$ repulsive interaction can increase the conductance for sufficiently strong disorder



## Application to the conductance of atomic chains



possible explanantion of conductance oscillations as a function of length in break junction contacts [R. A. Molina, D. Weinmann, J.-L. Pichard, Europhys. Lett. 67, 96 (2004)]



Persistent current

Even-odd effects Disorder & interaction



Persistent current

Even-odd effects

Atomic chains

### Even-odd effects in atomic chains 1.1 1.05 Au 1 Persistent current 0.95 conductance (2e<sup>2</sup>/h) Test of the method 2 Pt R. H. M. Smit et al., 1.5 Even-odd effects Phys. Rev. Lett. 91, 076805 (2003) Atomic chains 2.2 Ir 2 1.8 1.6 0.8 0 0.2 0.4 0.6 1.2 1 1.4 length (nm) Length-dependent oscillations R. A. Molina et al., Europhys. Lett. 67, 96 (2004) 1.0 Persistent curren 0.8 0.6 в 0.4 - U=1 0.2 U=2 ۸ U=40.0 Even-odd effects 10 12 14 2 4 6 8 16 18 20 22 24 L Atomic chains 1.0 1.0 0.8 0.8 0.6 0.6 д 0.4 0.4 U=10.2 0.2 Ě U=2U=4 0.0 0.0 2 2 4 8 10 12 14 16 4 10 12 14 16 6 6 8 LL

Even-odd effects

Conclusions

### Period of oscillation finite interaction: 1.0 1.0 1.0 Persistent current 0.8 0.8 0.8 б 0.6 0.6 0.6 U=1 $\nu = 1/3$ $\nu = 1/4$ $\nu = 1/5$ U=4Test of the method 4 6 8 10 12 4 6 8 10 12 6 8 10 12 14 16 L L Even-odd effects non-interacting: 1.0 1.0 1.0 Atomic chains 0.8 0.8 0.8 д 0.6 0.6 0.6 $\nu = 1/3$ $\nu = 1/4$ $\nu = 1/5$ 2 4 6 8 10 2 4 6 8 10 4 8 10 2 6 L L L Conclusions $\phi$ Persistent curren

### embedding method

- close an interacting system to a ring by means of a noninteracting lead
- interacting region can be described by an effective point scatterer
- residual conductance can be obtained from the persistent current or charge stiffness
- Phys. Rev. B 67, 235306 (2003)
- Eur. Phys. J. B **39**, 107 (2004)